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Wanli Jiang; Vinnakota, B.;  
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---

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*Thomas, N.J.; Cruickshank, D.G.M.; Laurenson, D.I.;*

3G Mobile Communication Technologies, 2000. First International Conference (IEE Conf. Publ. No. 471) , 27-29 March 2000

Pages:446 - 450

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---

**6 Describing multifunction adaptive phased array radars**

*Collinson, A.; Goodenough, S.;*

Radar System Modelling (Ref. No. 1998/459), IEE Colloquium on , 8 Oct. 199

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[\[Abstract\]](#) [\[PDF Full-Text \(272 KB\)\]](#) IEEE CNF

---

**7 3D simulation of sputter deposition of titanium layers in contact holes with high aspect ratios**

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Materials for Advanced Metallization, 1997. MAM '97 Abstracts Booklet., European Workshop , 16-19 March 1997

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---

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Wireless Communications, IEEE Transactions on , Volume: 1 , Issue: 2 , April

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---

**9 IC test using the energy consumption ratio**

*Wanli Jiang; Vinnakota, B.;*

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on , Volume: 19 , Issue: 1 , Jan. 2000

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---

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**11 Formation of voids in silicone RTV dispersion under beam-irradiated silicon integrated circuits**

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Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [ also IEEE Trans. on Components, Packaging, and Manufacturing Technology, A, B, C] , Volume: 13 , Issue: 2 , June 1990  
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---

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Circuits, Devices and Systems, IEE Proceedings [see also IEE Proceedings G-Circuits, Devices and Systems] , Volume: 144 , Issue: 2 , April 1997  
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*Sang-Youb Kim; Guanghan Xu;*

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---

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---

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VLSI Test Symposium, 2003. Proceedings. 21st , 27 April-1 May 2003  
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... Output/Input Capacitance **ratio** of each stage ... Short **circuit** - may change as shorted output changes. ... will detect all possible stuck-at **faults** (100% **fault coverage**). ...

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### ASIC Guide Glossary

... **fault coverage** The **ratio** of the count of all detectable **faults** in a **circuit** to the count of those **faults** detected by a particular test set (set of test ...

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### Section Three: Chapter Two

... A measure called "**fault coverage**" determines a **fault** test set quality ... This measure comes from the **ratio** of the number of **circuit** nodes controlled and ...

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### [PDF] Testing for Bridging Faults

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... when  $x \neq y$  depends on the **ratio** of pull ... adequate **BF coverage** and therefore **BF coverage** estimation is ... The detection of bridging **faults** (equivalent to stuck-on ...

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... B. However, set A has to target on transition **faults**. ... set that can provide a complete topological (site) **coverage**. ...  $D_j$  where  $\epsilon$  denotes the **ratio** of partition ...

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... of financial information, An introduction to **Ratio** Analysis and ... on quality, The effect of **fault coverage** on quality. ... D3\_1, el, Clocking **circuits** and **timing**, Clocking ...

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... logic Performance (**timing**) Occurrence frequency (%) 51 1 6 13 6 8 5 5 5 Ref.: J.

Bateson, In-Circuit Testing, Van Nostrand Reinhold, 1985. Page 11. **Fault** Model ...

www.ece.concordia.ca/~kasiar/fmod.pdf - [Similar pages](#)

### Logic Design for Array-Based Circuits - DE White - eBook

... Recommended **coverage** is 90% or higher ... simulator systems, but modeling differences make comparisons of **fault** grade scores ... that have a non-one to one **ratio** to pads ...

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### Medical Electronics Test - August 1995 - Cardiac Pacemakers

... to turn transistors off since these **faults** result in ... but limited by the signal-to-noise **ratio** of the ... it decreases test times without sacrificing test **coverage**. ...

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